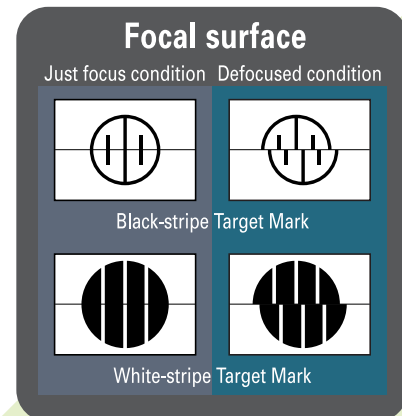
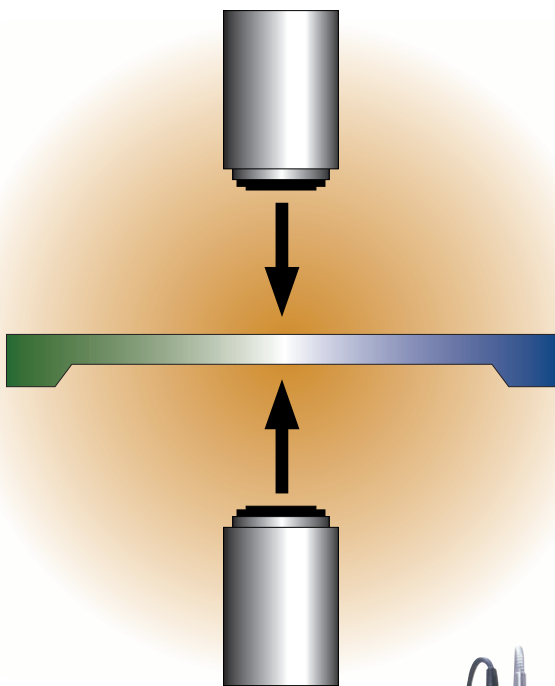


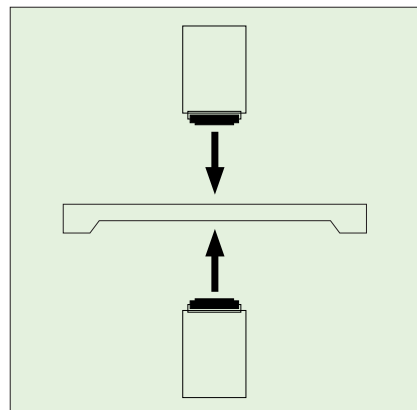
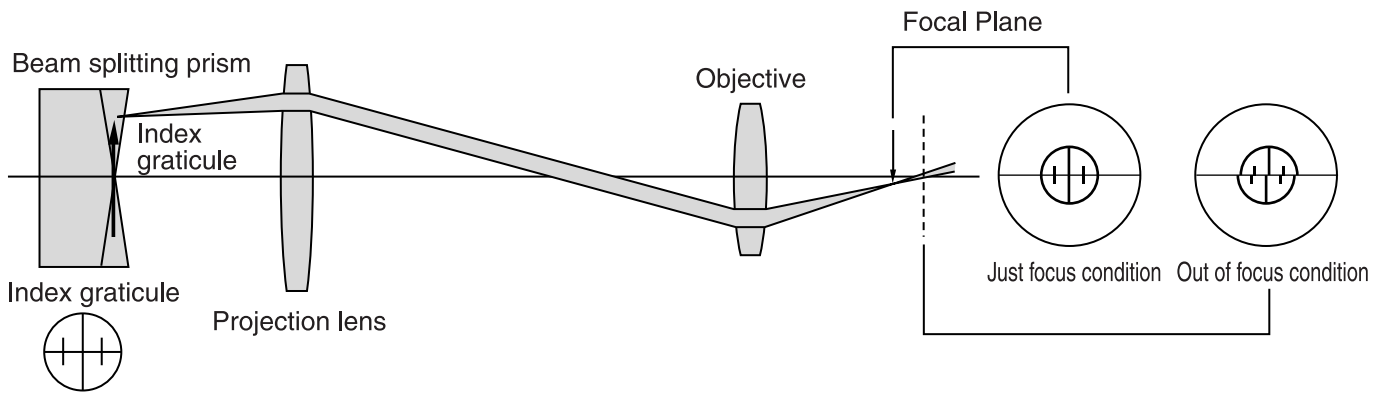
Non-Contact Thickness Measuring Microscope System

THS Series

Specially designed focus indicator (Target Mark) facilitates focusing operation greatly. Highly accurate and repeatable measurement is possible. No discrepancies between operators occur.



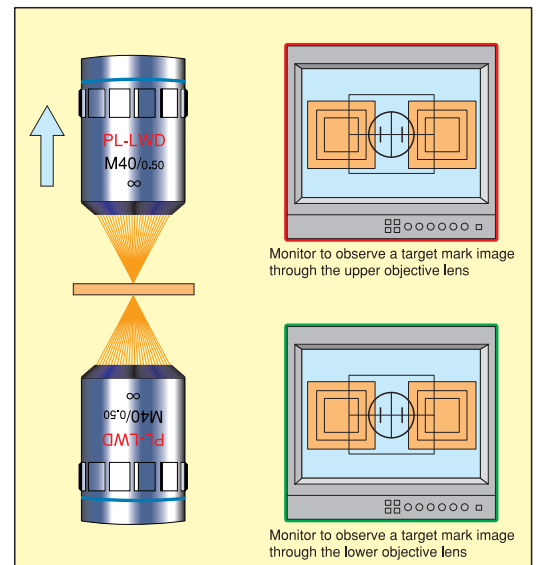
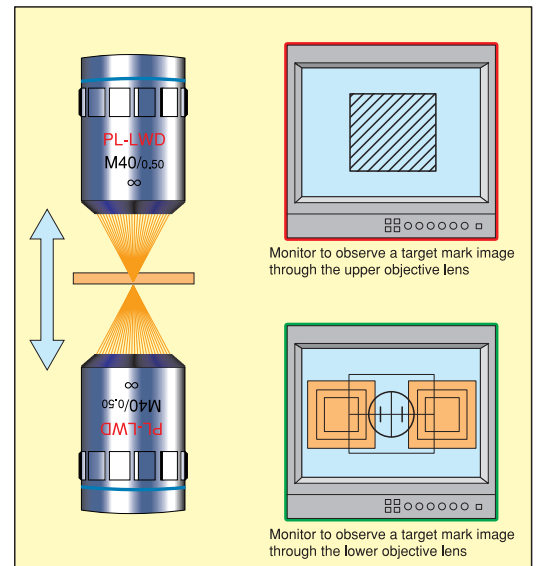
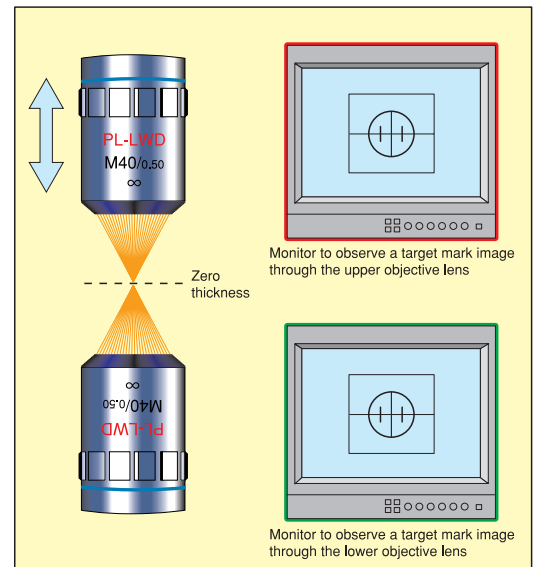
te with optical method



Thickness Measurement

Method

1. First bring the target mark into focus by moving the upper optical system vertically without placing an object on the stage, and identify the target mark on the two separate TV monitors. Then, zero reset the Z-axis digital counter.
2. Place a specimen on the microscope stage, and move the lower optical system to focus on the bottom side of the specimen.
3. Focus on the upper surface of a specimen by moving the upper optical system. The quantity of the movement of the upper optical system is measured as a thickness of the specimen.

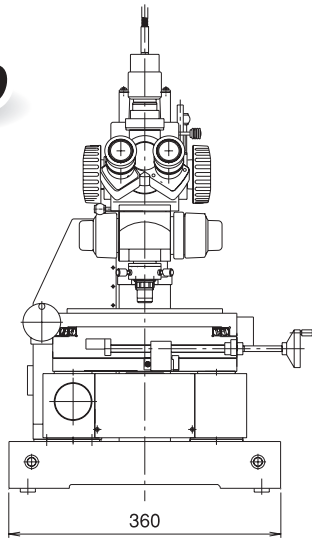


Applications

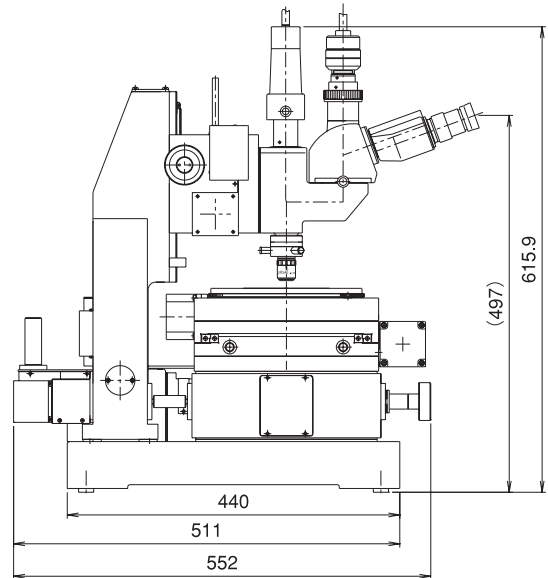
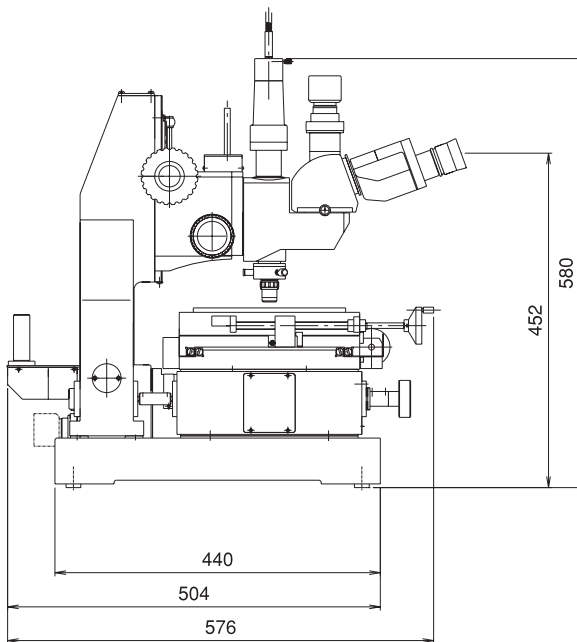
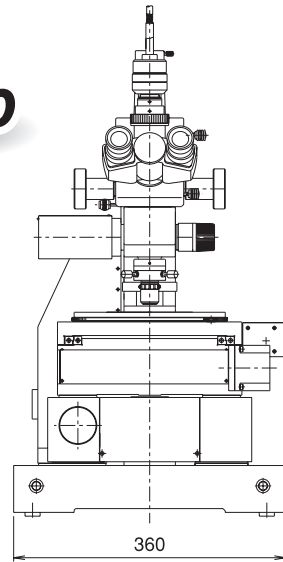
Semiconductor parts	Silicon wafers, lead frame fingers, etc.
Electronic parts	Printed circuit boards, Hybrid IC steps, etc.
Others	Lid of can, aluminum sheet, magnetic tapes, photographic films, etc.

External Dimensions

THS-10



THS-20



Specifications

Model	THS-10	THS-20	THS-206	THS-208
Measuring Method	Manual	Auto		
Size of specimen	4 inches		6 inches	8 inches
Measuring area	X : 100 mm Y : 100 mm		X : 150 mm Y : 150 mm	X : 200 mm Y : 200 mm
Resolution	1 μ m	0.1 μ m		
Repeatability	-	1 σ = 0.5 μ m (testing block gauge)		

●All specifications are subject to change without prior notice.

UNION OPTICAL CO., LTD.

2-19-17, Shimura, Itabashi-Ku, Tokyo 174-0056 Japan
 Tel : 81-3-3966-2206 Fax : 81-3-3966-2230
 E-mail;sales@union.co.jp
 URL;http://www.union.co.jp